


<b>Search Notes</b>  	<b>Application/Control No.</b>  10578082	<b>Applicant(s)/Patent Under Reexamination</b>  OHTSUJI, TAKAMASA
	<b>Examiner</b>  Hai H Huynh	<b>Art Unit</b>  3747

SEARCHED			
Class	Subclass	Date	Examiner
123	336	6-25-07	HHH
123	337	6-25-07	HHH
123	73A	6-25-07	HHH
123	73AD	6-25-07	HHH
123	398	6-25-07	HHH
123	400	6-25-07	HHH
123	442	6-25-07	HHH
update	search	3-13-08	HHH
123	342	7-14-08	HHH
261	23.1	7-14-08	HHH
261	23.2	7-14-08	HHH
261	41.1	7-14-08	HHH
261	41.2	7-14-08	HHH
261	41.3	7-14-08	HHH

SEARCH NOTES			
Search Notes		Date	Examiner
EAST		6-25-08	HHH
		3-13-08	HHH
		7-14-08	HHH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
above	search	7-14-08	HHH